

Notice of References Cited	Application/Control No. 10/605,448		Applicant(s)/Patent Under Reexamination BEYER ET AL.	
	Examiner Dennis Myint		Art Unit 2162	Page 1 of 1

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*	B	US-2003/0110150	06-2003	O'Neil et al.	707/1
*	C	US-2003/0130981	07-2003	Nehru et al.	707/1
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.